TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (Ultra-High-Speed U-MOSIII)

### **TPC8020-H**

High-Efficiency DC/DC Converter Applications

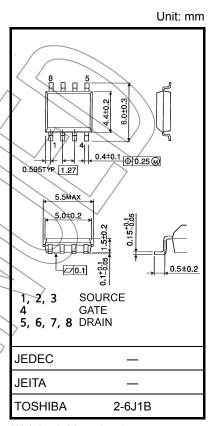
Notebook PC Applications

Portable Equipment Applications

- Small footprint due to a small and thin package
- High-speed switching
- Small gate charge: QSW = 6.9 nC (typ.)
- Low drain-source ON- resistance: RDS (ON) =  $6.8 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 32 S$  (typ.)
- Low leakage current:  $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 30 \text{ V)}$
- Enhancement mode:  $V_{th} = 1.1$  to 2.3 V ( $V_{DS} = 10$  V,  $I_{D} = 1$  mA)

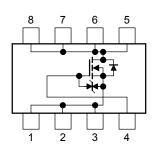
## Absolute Maximum Ratings (Ta = 25°C)

			/		
Characteristic		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	30	\ \ \	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		Voge	30	A	
Gate-source voltage		V <sub>GSS</sub>	±20	٧	
Drain current	DC (Note 1)	É	13	$\rightarrow_{A}$	
Diain current	Pulsed (Note 1)	I <sub>DP</sub>	52	^	
Drain power dissipation (t = 10 s)		PD	1.9	W	
(Note 2a)		1,0	1,5		
Drain power dissipation (t = 10 s) (Note 2b)		PD	1.0	W	
Single-pulse avalanche energy (Note 3)		EAS	110	mJ	
Avalanche current		TAR	13	Α	
Repetitive avalanche energy (Note 2a) (Note 4)		EAR	0.084	mJ	
Channel temperature		T <sub>ch</sub> 150		°C	
Storage temperature range		T <sub>stg</sub>	–55 to 150	°C	



Weight: 0.085 g (typ.)

#### **Circuit Configuration**



Note: For Notes 1 to 4, refer to the next page.

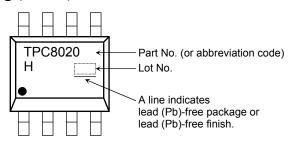
Using continuously under/heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

#### **Thermal Characteristics**

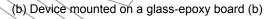
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to ambient $(t=10\;s) \eqno(Note\;2a)$	R <sub>th (ch-a)</sub>	65.8	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	125	°C/W

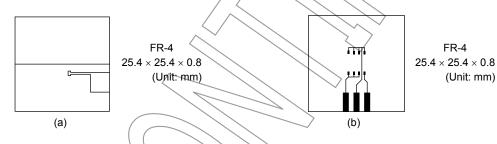
### Marking (Note 5)



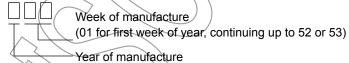
Note 1: The channel temperature should not exceed 150°C during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)





- Note 3:  $V_{DD} = 24 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 0.5 mH,  $R_G = 25 \Omega$ ,  $I_{AR} = 13 \text{ A}$
- Note 4: Repetitive rating; pulse width limited by max channel temperature
- Note 5: on the lower left of the marking indicates Pin 1.
  - \* Weekly code: (Three digits)



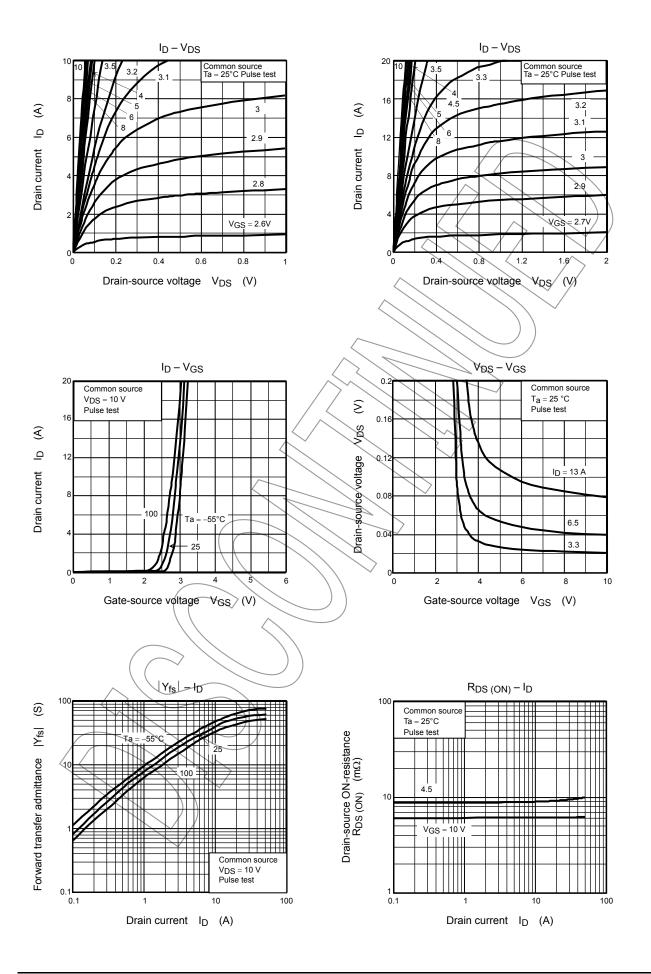
(The last digit of the calendar year)

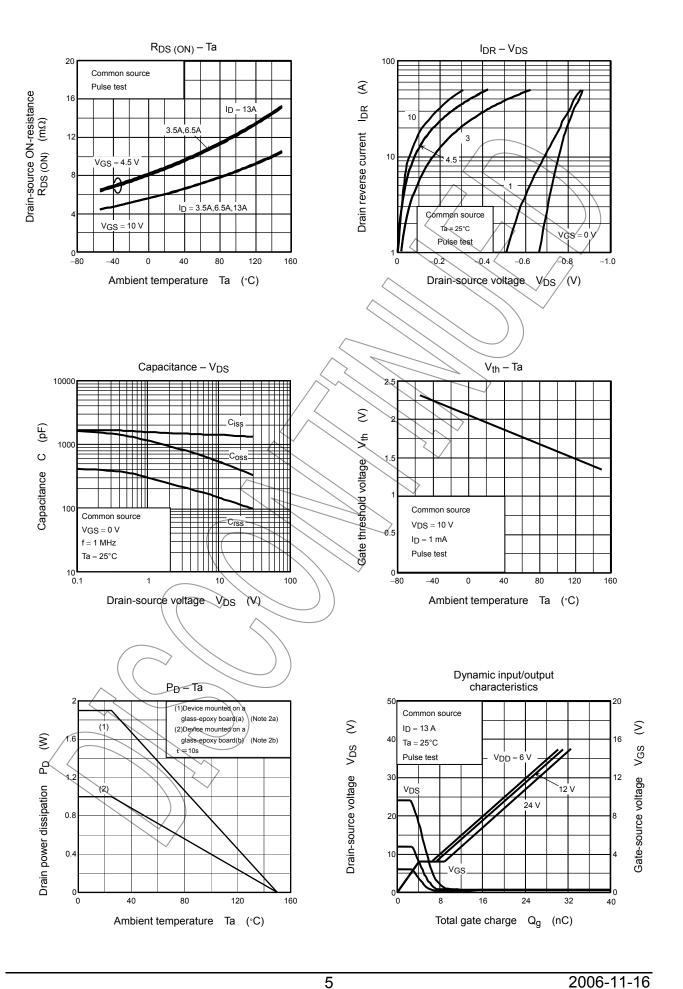
### **Electrical Characteristics (Ta = 25°C)**

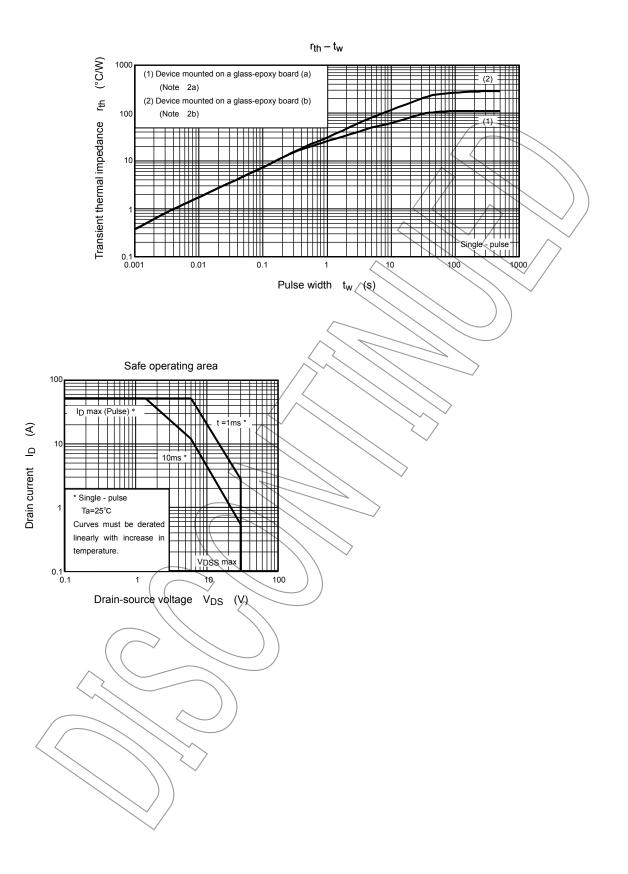
Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cutoff curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_		V
		V <sub>(BR)DSX</sub>	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15_	_	_	V
Gate threshold ve	oltage	$V_{th}$	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$	1.1	\_	2.3	V
Drain-source ON-resistance		P= - (-)	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 6.5 A		9.5	13	mΩ
		R <sub>DS</sub> (ON)	$V_{GS} = 10 \text{ V}, I_D = 6.5 \text{ A}$	1	6.8	9	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 6.5 \text{ A}$	16	32	(+)	S
Input capacitance	е	C <sub>iss</sub>		/	1395	\ }	
Reverse transfer	capacitance	C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	¥	140/	,	pF
Output capacitance		Coss			525 /	_	
Switching time	Rise time	t <sub>r</sub>	10 V □ 1D=6.5 A	+	3	_	
	Turn-on time	t <sub>on</sub>	VGS ØV VOUT		9	_	ns
	Fall time	t <sub>f</sub>	R R W W.77	>-	8	_	115
	Turn-off time	t <sub>off</sub>	V <sub>DD</sub> ≃ 15 V Duty ≦ 1%, t <sub>w</sub> = 10 μs	_	29	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} \neq 13 \text{ A}$	_	23	_	
			$V_{DD} \simeq 24 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 13 \text{ A}$		13		
Gate-source cha	rge 1	Q <sub>gs1</sub>			4.5		nC
Gate-drain ("Miller") charge		Qgd	$V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$	_	4.9	_	
Gate switch char	ge	Qsw		_	6.9	_	

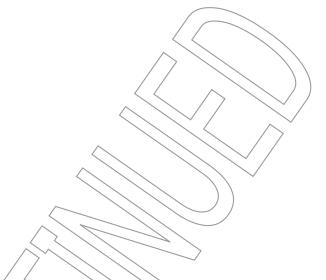
# Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current Pulse (Note 1)	IDRP	_	_	_	52	Α
Forward voltage (diøde)	VDSF	$I_{DR} = 13 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.2	V









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